

# Issue Classification



Application/Control No. 10500603		Applicant(s)/Patent under Reexamination OOSAWA ET AL.
Examiner Hanan, Devin		Art Unit 3745

ORIGINAL		INTERNATIONAL CLASSIFICATION				
CLASS	SUBCLASS	CLAIMED			NON-CLAIMED	
415	68	F	0	4	D	25 / 16
		F	0	1	D	1 / 24
CROSS REFERENCE(S)						
SUBCLASS (ONE SUBCLASS PER BLOCK)						
CLASS						
415	199.5					
416	126					
	198R					
Devin Hanan <i>Devin Hanan</i> (Assistant Examiner)		Total Claims Allowed: 12				
7/28/2006 7/28/2006 (Date)		EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 2/28/06				
(Legal Instruments Examiner)		(Primary Examiner)			O.G. Print Claim(s) 1	O.G. Print Figure 1